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nSpec Version 0.24.2.6

Release Date: 25 Feb 2025

Documentation Updated: 07 Mar 2025

Overview

nSpec patch release v0.24.2.6 includes bug fixes for nView. It also introduces a pre-release version of Gen V AI Analysis, available on a case-by-case basis by special request to support@nanotronics.ai

Upgrading to v0.24.2.6

> ⚠ Library Update Required to enable Gen V AI Analysis & new nTelligence

If upgrading from a version more than 1 release prior, please reference all intermediate release notes for upgrade steps *for each version*.

A library update is not strictly required for core changes and bug fixes included in this release. However, for any customers looking to utilize the pre-release version of Gen V AI, some manual installation steps must be taken. Please contact support@nanotronics.ai to inquire about obtaining Gen V AI access during the pre-release period.

New Features

Highlights

NSPEC-9113: Improve repeatability of camera rotation

Repeatability should be improved for < 0.1 degree theta rotations. In previous versions a 0.05 degree parametric move will likely not change the image, whereas that *should* now move the edge of a field of view by a couple pixels, and you should observe improved consistency.

New Features Changelog

T	Key	Release Notes Summary
	NSPEC-9113	Improve repeatability of camera rotation

1 issue Refresh

Bug Fixes

Highlights

NSPEC-9012: Device Yield Report can Error if no FallThrough bin Specified

Prior to this fix, if a Device Yield nJson file specified a non-existent id as its `FallThrough` bin, nView would fail to properly render the Device Yield report. This fix adds additional integrity checks, and fails the analysis if the FallThrough bin is improperly specified. nView will also fail with more informative messages to help correct the issue within the nJson file.

NSPEC-9068: nView cannot open line-type defect reports

Prior to this fix, nView would crash if you attempted to open a line-type defect report.

NSPEC-9017: Flat Field on transposed non-square images is not persistent

Following recent enhancements to the handling of binning within flat field correction, an edge case existed where flat fields would not persist across nSpec sessions if the following were true:

1. Camera Crop was non-square
2. Transpose Images = 1
3. Flip Images Vertically = 1

Changelog

T	Key	Release Notes Summary	Affected Releases
	NSPEC-9012	Device Yield Report can Error if no FallThrough bin Specified	0.24.2.1, 0.24.2.2, 0.24.2.3
	NSPEC-9068	nView cannot open line-type defect reports	0.24.2.2, 0.24.2.3
	NSPEC-9107	Flat Field on transposed non-square images is not persistent	0.24.2.0, 0.24.2.1, 0.24.2.2, 0.24.2.3, 0.24.2.4

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